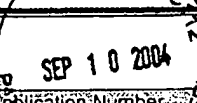



In place of PTO-1449 Form		U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Application Number		10/816,730	
				Filing Date		April 2, 2004	
				Applicant(s)		Chun-Chieh Lin	
				Art Unit		2818	
				Examiner Name		To Be Determined	
SHEET 1 OF 1				Attorney Docket Number		24061.188 (TSMC2003-1374)	

U. S. PATENT DOCUMENTS				
Examiner's Initials	Cite No.	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
ak	AA	5956267	09-21-1999	Hurst, et al.
	AB	6005800	12-21-1999	Koch, et al.
	AC	6114719	09-05-2000	Dill, et al.
	AD	6335890	01-01-2002	Reohr, et al.
	AE	6368878	04-09-2002	Abraham, et al.
	AF	6417561	07-09-2002	Tuttle
	AG	6430084	08-06-2002	Rizzo, et al.
	AH	6475812	11-05-2002	Nickel, et al.
	AI	6490217	12-03-2002	DeBrosse, et al.
	AJ	6509621	01-21-2003	Nakao
	AK	6515897	02-04-2003	Monsma, et al.
	AL	6522579	02-18-2003	Hoenigschmid
	AM	6525957	02-25-2003	Goronkin, et al.
	AN	6555858	04-29-2003	Jones, et al.
	AO	6567299	05-20-2003	Kunikiyo, et al.
	AP	6590803	07-08-2003	Saito, et al.
	AQ	6594191	07-15-2003	Lammers, et al.
	AR	6621731	09-16-2003	Bessho, et al.
	AS	6661689	12-06-2003	Asao, et al.
	AT	6667899	12-23-2003	Subramanian, et al.
ak	AU	6693822	02-17-2004	Ito
	AV	6693826	02-18-2004	Black, Jr., et al.
	AW	2002/0105827 A1	08-08-2002	Redon, et al.
	AX	2003/0048676 A1	03-13-2003	Daughton, et al.
	AY	2003/0086313 A1	05-08-2003	Asao
	AZ			

FOREIGN PATENT DOCUMENTS					
Examiner's Initials	Cite No.	Foreign Patent Document (Country Code - Number - Kind)	Publication Date MM-DD-YYYY	Patentee or Applicant of Cited Document	Translation Y/N

OTHER PRIOR ART				
Examiner's Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item, date, page(s), volume, issue number(s), publisher, city/country where published		
ak	BA	SAITO, YOSHIKI, ET AL., "Correlation Between Barrier Width, Barrier Height, and DC Bias Voltage Dependencies on the Magnetoresistance Ratio in Ir-Mn Exchange Biased Single and Double Tunnel Junctions", The Japan Society of Applied Physics, Vol. 39, 2000, pp. L1035-L1038.		
ak	BB	MONTAIGNE, F., ET AL., "Enhanced Tunnel Magnetoresistance at High Bias Voltage in Double-Barrier Planar Junctions", Applied Physics Letters, Vol. 73, No. 19, November 9, 1998, pp. 2829-2831.		
ak	BC	ANGUELOUCH, A., "Two-Dimensional Magnetic Switching of Micron-Size Films in Magnetic Tunnel Junctions", Applied Physics Letters, Vol. 76, No. 5, January 31, 2000, pp. 622-624.		

Examiner Signature		Date Considered	04/11/05
--------------------	---	-----------------	----------

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.